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Table of Contents

Electrical Measurement of On-Mask Mismatch Resistor Structures	1
<i>S. Smith, A. Tsiamis, M. McCallum, A. C. Hourd, J. T. M. Stevenson and A. J. Walton</i>	
A Systematic Approach to Accurate Evaluation of CD-Metrology Tools.....	7
<i>Ndubuisi G. Orji, Benjamin D. Bunday, Ronald G. Dixson and John A. Allgair</i>	
Extraction of Sheet Resistance and Linewidth from All-Copper ECD Test Structures Fabricated from Silicon Preforms.....	12
<i>B. J. R. Shulver, A. S. Bunting, A. M. Gundlach, L. I. Haworth, A. W. S. Ross, S. Smith, A. J. Snell, J. T. M. Stevenson, A. J. Walton, R. A. Allen and M. W. Cresswell</i>	
Study of Test Structures for Use as Reference Materials for Optical Critical Dimension Applications.....	18
<i>Richard A. Allen, Heather J. Patrick, Michael Bishop, Thomas A. Germer, Ronald Dixson, William F. Guthrie and Michael W. Cresswell</i>	
A New Test Structure for Shallow Trench Isolation (STI) Depth Monitor	24
<i>Qingfeng Wang, Sameer Pendharkar, Binghua Hu, Bill Russell and Pam Jones-Williams</i>	
FUSI Specific Yield Monitoring Enabling Improved Circuit Performance and Fast Feedback to Production	27
<i>T. Chiarella, M. Rosmeulen, H. Tigelaar, C. Kerner, A. Nackaerts, J. Ramos, A. Lauwers, A. Veloso, M. Jurczak, A. Rothschild, L. Witters, H. Yu, J. A. Kittl, R. Verbeeck, M. de Potter, I. Debusschere, P. Absil, S. Biesemans, T. Hoffmann</i>	
Test Circuit for Study of CMOS Process Variation by Measurement of Analog Characteristics.....	31
<i>Karen M. G. V. Gettings and Duane S. Boning</i>	
Ring Oscillator Based Test Structure for NBTI Analysis	36
<i>Mark B. Ketchen, Manjul Bhushan and Ronald Bolam</i>	
A Precise Resistance Tracing Technique for a Toggle Mode MRAM Evaluation	42
<i>Y. Katoh, K. Tsuji, H. Hada and N. Kasai</i>	
Electrical Failure Analysis Methodology for DRAM of 80nm era and beyond using Nanoprober Technique	46
<i>Hyunho Park, Sang-Yeon Han, Won-Seok Lee, Chang-Hoon Jeon, Siok Sohn, Kyosuk Chae, Satoru Yamada, Wouns Yang and Donggun Park</i>	
New Methodology for the Characterization of EEPROM Extrinsic Behaviors.....	50
<i>Djafer Medjahed, Thierry Yao, Dominique Wojciechowski, Pierre Gassot, Michael Yameogo</i>	
A 1 Mbit SRAM test structure to analyze local mismatch beyond 5 sigma variation	54
<i>Thomas Fischer, Christopher Otte, Doris Schmitt-Landsiedel, Ettore Amirante, Alexander Olbrich, Peter Huber, Martin Ostermayr, Thomas Nirschl, Jan Einfeld</i>	
Impact of Sinter Process and Metal Coverage on Transistor Mismatching and Parameter Variations in Analog CMOS Technology	58
<i>Xiaojie Wu, Joe Trogolo, Flex Inoue, Zhenwu Chen, Pam Jones-Williams, Imran Khan, Praful Madhani</i>	
Rapid Characterization of Threshold Voltage Fluctuation in MOS Devices	63
<i>Kanak Agarwal, Sani Nassif, Frank Liu, Jerry Hayes, Kevin Nowka</i>	
Impact of Transistor Matching on Features of Digital Circuit Blocks	67
<i>U. Schaper, T. Kodytek, W. Kamp, R. Kunemund</i>	
Understanding the Carbon Impact on Si/SiGe:C HBT Base Current Mismatch	72
<i>Stéphane Danaie, Mathieu Marin, Gérard Ghibaudo, Jean-Charles Vildeuil, Stéphanie Chouteau, Isabelle Sicard, Augustin Monroy</i>	
Automatic extraction methodology for accurate measurement of effective channel length on 65nm MOSFET technology and below.....	76
<i>Dominique Fleury, Antoine Cros, Krunoslav Romanjek, David Roy, Franck Perrier, Benjamin Dumont, Hugues Brut</i>	

Table of Contents

Faster ESD device characterization with wafer-level HBM.....	80
<i>M.Scholz, D. Tremoullies, D. Linten, Y. Rolain, R. Pintelon, M. Sawada, T. Nakaei, T. Hasebe, G. Groeseneken</i>	
A New Combined Methodology for Write-Margin Extraction of Advanced SRAM.....	84
<i>Nicolas Gierczynski, Bertrand Borot, Nicolas Planes, Hugues Brut</i>	
Scalable approach for external collector resistance calculation	88
<i>C. Raya, N. Kauffmann, F. Pourchon, D. Celi, T. Zimmer</i>	
Analog characterization of dielectric relaxation of MIM capacitor using an improved recovery voltage technique.....	94
<i>Zhenqiu Ning, Herman Casier, Renaud Gillon, H-X Delecourt, Dimitri Tack, Erwin de Vylder, Patrick van Torre and Dan Hegsted</i>	
Modeling the Mismatch of High-k MIM Capacitors	100
<i>Mathieu Marin, Sébastien Cremer, Jean-Christophe Giraudin and Bertrand Martinet</i>	
Gate Oxide Leakage and Floating Gate Capacitor Matching Test	105
<i>Weidong Tian, Joe Trogolo, Bob Todd and Lou Hutter</i>	
Test Structures for Accurate UHF C-V Measurements of Nano-Scale CMOSFETs with HfSiON and TiN Metal Gate	109
<i>Kyong-Taek Lee, Jurriaan Schmitz, George A. Brown, Dawei Heh, Rino Choi, Rusty Harris, Seung-Chul Song, Byoung Hun Lee, In-Shik Han, Hi-Deok Lee and Yoon-Ha Jeong</i>	
A Large Scale, Flip-Flop RAM imitating a logic LSI for fast development of process technology	113
<i>M. Fujii, K. Nii, H. Makino, S. Ohbayashi, M. Igarashi, T. Kawamura, M. Yokota, N. Tsuda, T. Yoshizawa, T. Tsutsui, N. Takeshita, N. Murata, T. Tanaka, T. Fujiwara, K. Asahina, M. Okada, K. Tomita, M. Takeuchi and H. Shinohara</i>	
Development and Use of Small Addressable Arrays for Process Window Monitoring in 65nm Manufacturing	117
<i>Muthu Karthikeyan, Arthur Gasasira, Stephen Fox, Greg Yeric, Michael Hall, John Garcia, Barry Mitchell and Eric Wolf</i>	
Test Structure for Process and Product Evaluation	122
<i>F. Rigaud, J. M. Portal, H. Aziza, D. Née, J. Vast, C. Auricchio, B. Borot</i>	
Device Array Scribe Characterization Vehicle Test Chip for Ultra Fast Product Wafer Variability Monitoring.....	127
<i>Christopher Hess, Sharad Saxena, Hossein Karbasi, Senthil Subramanian, Michele Quarantelli, Angelo Rossoni, Stefano Tonello, Sa Zhao, Dustin Slusher</i>	
A Test Structure for Analysis of Asymmetry and Orientation Dependence of MOSFETs.....	132
<i>T. Matsuda, Y. Sugiyama, K. Nohara, K. Morita, H. Iwata, T. Ohzone, T. Morishita and K. Komoku</i>	
Automated on-wafer characterization in micro-machined resonators: towards an integrated test vehicle for bulk acoustic wave resonators (FBAR).....	136
<i>Humberto Campanella, Pascal Nouet, Pedro de Paco, Arantxa Uranga, Nuria Barniol and Jaume Esteve</i>	
Excess Base Current Model for Gamma-Irradiated SiGe Bipolar Transistors	141
<i>M. Ullán, J. P. Alegre, S. Díez, G. Pellegrini, F. Campabadal, M. Lozano, E. Lora-Tamayo</i>	
Array Based Test Structure for Optical-Electrical Overlay Calibration.....	144
<i>B. J. R. Shulver, R. A. Allen, A. J. Walton, M. W. Cresswell, J. T. M. Stevenson, S. Smith, A. S. Bunting, C. Dunare, A. M. Gundlach, L. I. Haworth, A. W. S. Ross and A. J. Snell</i>	
Development of Electrical On-Mask CD Test Structures Based on Optical Metrology Features.....	150
<i>A. Tsiamis, S. Smith, M. McCallum, A. C. Hourd, O. Toublan, J. T. M. Stevenson and A. J. Walton</i>	
Methodology for performing RF reliability experiments on a generic test structure.....	156
<i>Guido T. Sasse, Rein J. de Vries and Jurriaan Schmitz</i>	

Table of Contents

On-wafer RF Figure-of-Merit Circuit Block Design for Technology Development, Process Control and PDK Validation.....	162
<i>S. Minehane, J. Cheng, T. Nakatani, S. Moriyama, B. Aghdaie, M. Sengupta, S. Saxena, S. Winters, H. Karbasi, M. Quarantelli, S. Tonello and M. Redford</i>	
Differential P+/Nwell varactor High Frequency Characterization.....	166
<i>Yvan Morandini, Dario Rapisarda, Jean-Francois Larchanche and Christophe Gaquière</i>	
High-Q Slow-Wave Transmission Line for Chip Area Reduction on Advanced CMOS Processes.....	171
<i>Ivan C. H. Lai, Minoru Fujishima</i>	
Test Structure on SCR Device in Waffle Layout for RF ESD Protection.....	175
<i>Ming-Dou Ker and Chun-Yu Lin</i>	
Reducing AC impedance measurement errors caused by the DC voltage dependence of broadband high-voltage bias-tees	179
<i>M. P. J. Tiggelman, K. Reimann and J. Schmitz</i>	
The rectangular bipolar transistor tetrode structure and its application.....	185
<i>M. Schroter, S. Lehmann</i>	
Evaluation of 300 mm High Resistivity SOI UNIBOND™ material for RF applications up to millimeter wave using 65 nm CMOS SOI technology	189
<i>F. Giancesello, C. Raynaud, D. Gloria, S. Boret, B. Ghyselen and C. Mazure</i>	
Dynamic Analyses of Membranes and Thin Films on Wafer Level.....	193
<i>R. Gerbach, F. Naumann, M. Ebert, J. Bagdahn, J. Klattenhoff, C. Rembe</i>	
Quantitative analysis of Joule heating in surface micromachined Greek cross test structures.....	197
<i>S. Enderling, S. Smith, J. T. M. Stevenson and A. J. Walton</i>	
Improved Test Structure for Thermal Resistance Scaling Study in Power Devices	201
<i>Anna Canepari, Guillaume Bertrand, Alexandre Giry, Michel Minondo, Sylvie Ortolland, Hervé Jaouen, Bertrand Szelag, Jocelyne Mourier, Jean-Pierre Chante</i>	
A Continuous Model for MOSFET VT Matching Considering Additional Length Effects.....	205
<i>Samuel Bordez, Augustin Cathignol, Krysten Rochereau</i>	
From MOSFET Matching Test Structures to Matching Data Utilization: Not an Ordinary Task.....	209
<i>Augustin Cathignol, Samuel Bordez, Krysten Rochereau, Gérard Ghibaudo</i>	
A Transmission-Line Based Technique for De-Embedding Noise Parameters.....	213
<i>Kenneth H. K. Yau, Alain M. Mangan, Pascal Chevalier, Peter Schvan and Sorin P. Voinigescu</i>	
A Novel RF-WAT Test Structure for Advanced Process Monitoring in SOC Applications.....	219
<i>David C. Chen, Ryan Lee, Y. C. Liu, Mao Chyuan Tang, Gavin Chiang, Annie Kuo, C. S. Yeh, S. C. Chien, S. W. Sun</i>	
Accurate Inductance De-embedding Technique for Scalable Inductor Models.....	224
<i>Volker Blaschke and James Victory</i>	
Coupling on-wafer measurement errors and their impact on calibration and de-embedding up to 110 GHz for CMOS millimeter wave characterizations.....	229
<i>C. Andrei, D. Gloria, F. Danneville, P. Scheer and G. Dambrine</i>	
Benchmarking the PSP Compact Model for MOS Transistors.....	233
<i>Xin Li, Weimin Wu, Amit Jha, Gennady Gildenblat, Ronald van Langevelde, Geert D.J. Smit, Andries J. Scholten, Dirk B. M. Klaassen, Colin C. McAndrew, Josef Watts, Michael Olsen, Geoffrey Coram, Samir Chaudhry and James Victory</i>	
Novel parameter extraction method for low field drain current of nano-scaled MOSFETs	239
<i>Takuji Tanaka</i>	
A unified model for integrated resistors in CMOS technologies	242
<i>I. Aureli, D. Ventrice, C. Codegoni and P. Fantini</i>	

Table of Contents

- Extraction of Self-Heating Free I-V Curves Including the Substrate Current of PD SOI MOSFETs.....246**
Qiang Chen, Zhi-Yuan Wu, Richard Y. K. Su, Jung-Suk Goo, Ciby Thuruthiyil, Martin Radwin, Niraj Subba, Sushant Suryagandh, Tran Ly, Vineet Wason, Judy X. An and Ali B. Icel